

Search Notes

Application/Control No.

10/620,376

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

HAYASHI ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	34	7/24/2006	DWY
429	35	7/24/2006	DWY
429	36	7/24/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/24/2006	DWY